INTEGRATED CIRCUITS

DATA SHEET



74ABT16952 74ABTH16952

16-bit registered transceiver (3-State)

Product specification Supersedes data of 1995 Sep 28 IC23 Data Handbook





16-bit registered transceiver (3-State)

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FEATURES

- Two 8-bit registered transceivers
- Live insertion/extraction permitted
- Power-up 3-State
- 74ABTH16952 incorporates bus-hold data inputs which eliminate the need for external pull-up resistors to hold unused inputs
- Power-up reset
- Multiple V_{CC} and GND pins minimize switching noise
- Independent registers for A and B buses
- Output capability: +64mA/–32mA
- Latch-up protection exceeds 500mA per Jedec Std 17
- ESD protection exceeds 2000V per MIL STD 883 Method 3015 and 200V per Machine Model
- Bus-hold data inputs eliminate the need for external pull-up resistors to hold unused inputs

DESCRIPTION

The 74ABT16952 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

The 74ABT16952 is a dual octal registered transceiver. Two 8-bit registers store data flowing in both directions between two bidirectional buses. Data applied to the inputs is entered and stored on the rising edge of the Clock (nCPXX) provided that the Clock Enable (nCEXX) is Low. The data is then present at the 3-State output buffers, but is only accessible when the Output Enable (nOEXX) is Low. Data flow from A inputs to B outputs is the same as for B inputs to A outputs.

Two options are available, 74ABT16952 which does not have the bus-hold feature and 74ABTH16952 which incorporates the bus-hold feature.



QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS T _{amb} = 25°C; GND = 0V	TYPICAL	UNIT
t _{PLH} t _{PHL}	Propagation delay nCPBA to nAx or nCPAB to nBx	C _L = 50pF; V _{CC} = 5V	2.8 2.3	ns
C _{IN}	Input capacitance	V _I = 0V or V _{CC}	4	pF
C _{I/O}	I/O capacitance	$V_O = 0V$ or V_{CC} ; 3-State	7	pF
I _{CCZ}	Quiescent supply current	Outputs disabled; V _{CC} = 5.5V	500	μΑ
I _{CCL}	Quidocent supply current	Outputs LOW; V _{CC} = 5.5V	8	mA

ORDERING INFORMATION

ONDERWIND IN ONIN				
PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
56-Pin Plastic SSOP Type III	-40°C to +85°C	74ABT16952 DL	BT16952 DL	SOT371-1
56-Pin Plastic TSSOP Type II	-40°C to +85°C	74ABT16952 DGG	BT16952 DGG	SOT364-1
56-Pin Plastic SSOP Type III	-40°C to +85°C	74ABTH16952 DL	BH16952 DL	SOT371-1
56-Pin Plastic TSSOP Type II	-40°C to +85°C	74ABTH16952 DGG	BH16952 DGG	SOT364-1

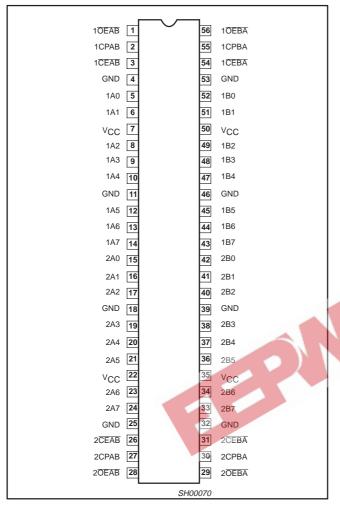
PIN DESCRIPTION

PIN NUMBER	SYMBOL	NAME AND FUNCTION
2, 55 18, 22	1CPAB / 1CPBA 2CPAB / 2CPBA	Clock input A to B / Clock input B to A
3, 54, 26, 31	1CEAB / 1CEBA 2CEAB / 2CEBA	Clock enable input A to B / Clock enable input B to A
52, 51, 49, 48, 47, 45, 44, 43 42, 41, 40, 38, 37, 36, 34, 33	1A0 – 1A7 2A0 – 2A7	Data inputs/outputs (A side)
1, 56 8, 29	1B0 – 1B7 2B0 – 2B7	Data inputs/outputs (B side)
4, 11, 18, 25, 32, 39, 45, 53	1 <u>OEAB</u> / 1 <u>OEBA</u> 2 <u>OEAB</u> / 2 <u>OEBA</u>	Output enable inputs
4, 17, 30, 43	GND	Ground (0V)
7, 22, 35, 50	V _{CC}	Positive supply voltage

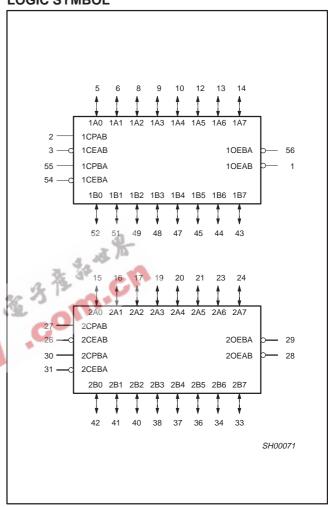
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PIN CONFIGURATION



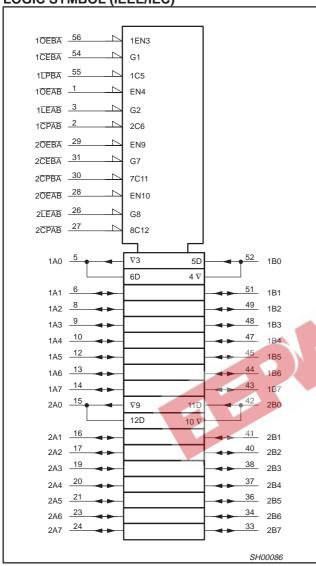
LOGIC SYMBOL



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FUNCTION TABLE for Register nAx or nBx

I	NPUTS		INTERNAL	OPERATING
nAx or nBx	nCPXX	nCEXX	Q	MODE
Х	Х	Н	NC	Hold data
L H	↑	L L	L H	Load data

H = High voltage level

L = Low voltage level

↑ = Low-to-High transition

X = Don't care

XX = AB or BA

NC=No change

FUNCTION TABLE for Output Enable

INPUTS	INTERNAL	nAx or nBx	OPERATING
nOEXX	Q	OUTPUTS	MODE
此作	Х	Z	Disable outputs
	Η	L	Enable outputs

H = High voltage level

L = Low voltage level

X = Don't care

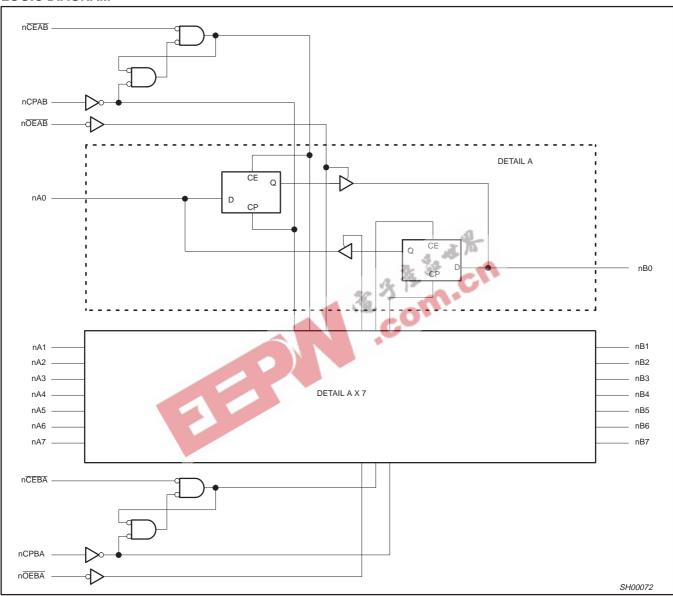
XX = AB or BA

Z = High impedance "off" state

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LOGIC DIAGRAM



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ABSOLUTE MAXIMUM RATINGS1, 2

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +7.0	V
I _{IK}	DC input diode current	V _I < 0	-18	mA
VI	DC input voltage ³		-1.2 to +7.0	V
lok	DC output diode current	V _O < 0	-50	mA
V _{OUT}	DC output voltage ³	Output in Off or High state	-0.5 to +5.5	V
la	DC output current	Output in Low state	128	mA
Гоит		Output in High state	-64	IIIA
T _{stg}	Storage temperature range		-65 to 150	°C

NOTES:

- 1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.
 The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIM	UNIT	
		MIN	MAX	
V _{CC}	DC supply voltage	4.5	5.5	V
VI	Input voltage	0	V _{CC}	V
V _{IH}	High-level input voltage	2.0		V
V _{IL}	Low-level Input voltage		0.8	V
I _{OH}	High-level output current		-32	mA
I _{OL}	Low-level output current		64	mA
Δt/Δν	Input transition rise or fall rate	0	10	ns/V
T _{amb}	Operating free-air temperature range	-40	+85	°C

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DC ELECTRICAL CHARACTERISTICS

						LIMITS			UNIT
SYMBOL	PARAM	ETER	TEST CONDITIONS	T _{ar}	_{nb} = +25	5°C	T _{amb} =	: –40°C 85°C	
				MIN	TYP	MAX	MIN	MAX	1
V _{IK}	Input clamp voltage $V_{CC} = 4.5V$; $I_{IK} = -18mA$			-0.9	-1.2		-1.2	V	
			$V_{CC} = 4.5V$; $I_{OH} = -3mA$; $V_I = V_{IL}$ or V_{IH}	2.5	2.9		2.5		V
V_{OH}	High-level output voltage $V_{CC} = 5.0V$; $I_{OH} = -3mA$; $V_I = V_{IL}$ or V_{IH}				3.4		3.0		V
			$V_{CC} = 4.5V$; $I_{OH} = -32mA$; $V_I = V_{IL}$ or V_{IH}	2.0	2.4		2.0		V
V_{OL}	Low-level output	voltage	$V_{CC} = 4.5V$; $I_{OL} = 64mA$; $V_I = V_{IL}$ or V_{IH}		0.42	0.55		0.55	V
V_{RST}	Power-up output	low voltage ³	$V_{CC} = 5.5V$; $I_{OL} = 1mA$; $V_I = GND$ or V_{CC}		0.13	0.55		0.55	V
I _I	Input leakage current	Control pins	V _{CC} = 5.5V; V _I = GND or 5.5V		±0.01	±1.0		±1.0	μА
	5		$V_{CC} = 4.5V, V_I = 0.8V$	50			50		
I_{HOLD}	Bus Hold current A inputs ⁶ 74ABTH16952		V _{CC} = 4.5V; V _I = 2.0V	-75			-75		μΑ
	7 17 18 11 11 0002		$V_{CC} = 5.5V$; $V_I = 0$ to $5.5V$	±500	0-				
I _{OFF}	Power-off leakag	je current	$V_{CC} = 0V$; V_O or $V_I \le 4.5V$	300	±5.0	±100		±100	μΑ
I _{PU/PD}	Power-up/down current4	3-State	$V_{\underline{CC}}$ = 2.1V; $V_{\underline{O}}$ = 0.0V; $V_{\underline{I}}$ = GND or $V_{\underline{CC}}$; $V_{\underline{OE}}$ = Don't care	C	±5.0	±50		±50	μА
I _{IH} + I _{OZH}	3-State output H	igh current	$V_{CC} = 5.5V$; $V_{O} = 5.5V$; $V_{I} = V_{IL}$ or V_{IH}		5.0	50		50	μΑ
I _{IL} + I _{OZL}	3-State output Lo	ow current	$V_{CC} = 5.5V$; $V_{O} = 0.0V$; $V_{I} = V_{IL}$ or V_{IH}		-5.0	-50		-50	μΑ
I _{CEX}	Output High leak	age current	$V_{CC} = 5.5V$; $V_O = 5.5V$; $V_I = GND$ or V_{CC}		5.0	50		50	μΑ
I _O	Output current ¹		$V_{CC} = 5.5V; V_{O} = 2.5V$	-50	-70	-180	-50	-180	mA
I _{CCH}			$V_{CC} = 5.5V$; Outputs High, $V_I = GND$ or V_{CC}		0.5	1.5		1.5	mA
I _{CCL}	Quiescent supply	v current	$V_{CC} = 5.5V$; Outputs Low, $V_I = GND$ or V_{CC}		8	19		19	mA
I _{CCZ}		13	$V_{CC} = 5.5V$; Outputs 3-State; $V_I = GND \text{ or } V_{CC}$		0.5	1.5		1.5	mA
ΔI_{CC}	Additional supply current per input pin ² 74ABT16952		V_{CC} = 5.5V; one input at 3.4V, other inputs at V_{CC} or GND		5	100		100	μА
ΔI_{CC}	Additional supply input pin ² 74ABT		V _{CC} = 5.5V; one input at 3.4V, other inputs at V _{CC} or GND		100	500		500	μА

- Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
 This is the increase in supply current for each input at 3.4V.
- 3. For valid test results, data must not be loaded into the flip-flops (or latches) after applying the power.
- 4. This parameter is valid for any V_{CC} between 0V and 2.1V with a transition time of up to 10msec. From V_{CC} = 2.1V to V_{CC} = 5V \pm 10% a transition time of up to 100 μ sec is permitted.
- 5. Unused pins at V_{CC} or GND.
 6. This is the bus hold overdrive current required to force the input to the opposite logic state.

AC CHARACTERISTICS

GND = 0V; $t_R = t_F = 2.5 \text{ns}$; $C_L = 50 \text{pF}$, $R_L = 500 \Omega$

SYMBOL	PARAMETER	WAVEFORM	T _a	_{amb} = +25° CC = +5.0°	C V	$T_{amb} = -40^{\circ}$ $V_{CC} = +5$	UNIT	
			MIN	TYP	MAX	MIN	MAX	
f _{MAX}	Maximum clock frequency	1	150			150		MHz
t _{PLH} t _{PHL}	Propagation delay nCPBA to nAx, nCPAB to nBx	1	1.0 1.0	2.8 2.3	3.9 3.9	1.0 1.0	4.3 4.3	ns
t _{PZH} t _{PZL}	Output enable time nOEBA to nAx, nOEAB to nBx	3 4	1.0 1.0	2.5 2.2	3.8 3.8	1.0 1.0	4.6 4.6	ns
t _{PHZ} t _{PLZ}	Output disable time nOEBA to nAx, nOEAB to nBx	3 4	1.7 1.3	3.4 2.6	4.4 3.9	1.7 1.3	5.2 4.2	ns

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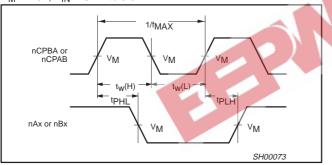
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AC SETUP REQUIREMENTS

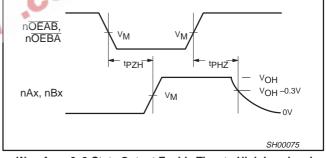
				LIMITS		
SYMBOL	PARAMETER	WAVEFORM	T _{amb} = V _{CC} =	+25°C +5.0V	T_{amb} = -40°C to +85°C V_{CC} = +5.0V \pm 0.5V	UNIT
			MIN	TYP	MIN	
t _S (H) t _s (L)	Setup time nAx to nCPAB or nBx to nCPBA	2	1.2 1.5	0.9 1.2	1.2 1.5	ns
t _h (H) t _h (L)	Hold time nAx to nCPAB or nBx to nCPBA	2	0.0 0.0	-1.2 -0.9	0.0 0.0	ns
t _s (H) t _s (L)	Setup time nCEAB to nCPAB, nCEBA to nCPBA	2	1.2 1.6	0.9 1.1	1.2 1.6	ns
t _h (H) t _h (L)	Hold time nCEAB to nCPAB, nCEBA to nCPBA	2	0.0 0.0	-1.1 -0.9	0.0 0.0	ns
t _w (H) t _w (L)	nCPAB or nCPBA pulse width, High or Low	1	3.3 2.5	2.6 1.0	3.3 2.5	ns

AC WAVEFORMS

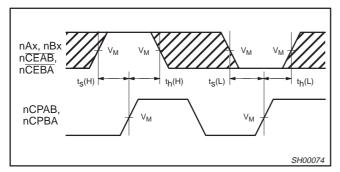
 $V_{M} = 1.5V$, $V_{IN} = GND$ to 3.0V



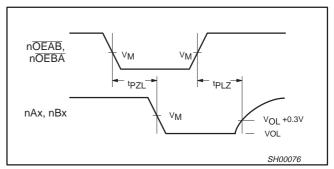
Waveform 1. Propagation Delay, Clock Input to Output, Clock Pulse Width, and Maximum Clock Frequency



Waveform 3. 3-State Output Enable Time to High Level and Output Disable Time from High Level



Waveform 2. Data Setup and Hold Times



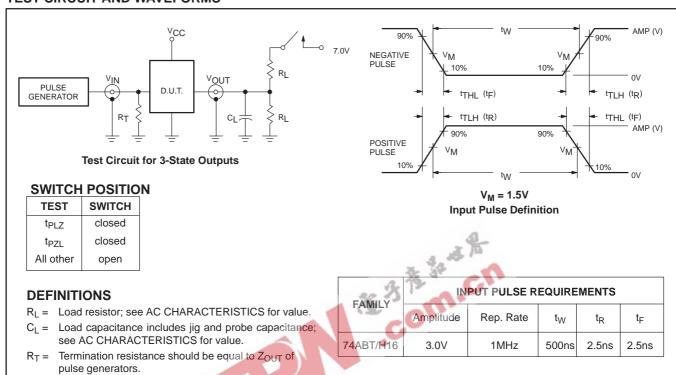
Waveform 4. 3-State Output Enable Time to Low Level and Output Disable Time from Low Level

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SA00018

TEST CIRCUIT AND WAVEFORMS

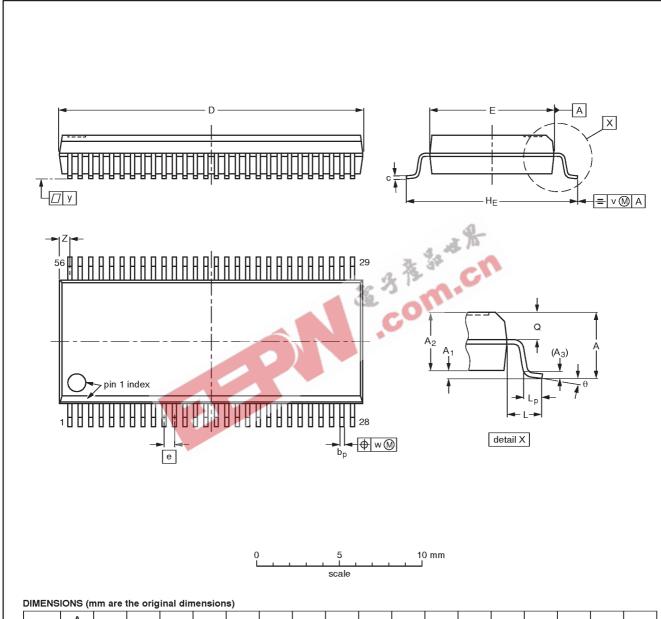


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SSOP56: plastic shrink small outline package; 56 leads; body width 7.5 mm

SOT371-1



UNIT	A max.	Α1	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽¹⁾	е	HE	L	Lp	Q	v	w	у	Z ⁽¹⁾	θ
mm	2.8	0.4 0.2	2.35 2.20	0.25	0.3 0.2	0.22 0.13	18.55 18.30	7.6 7.4	0.635	10.4 10.1	1.4	1.0 0.6	1.2 1.0	0.25	0.18	0.1	0.85 0.40	8° 0°

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

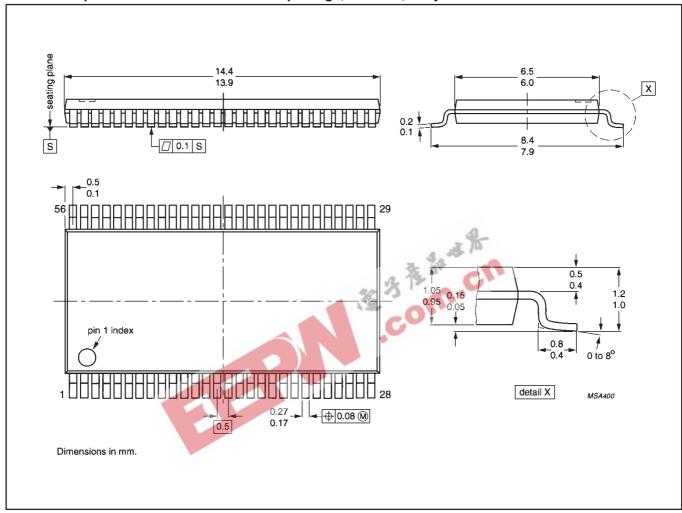
OUTLINE		REFER	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	EIAJ	PROJECTION	ISSUE DATE
SOT371-1		MO-118AB			93-11-02 95-02-04

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TSSOP56: plastic thin shrink small outline package; 56 leads; body width 6.1mm

SOT364-1



16-bit registered transceiver (3-State)

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Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
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^[1] Please consult the most recently issued datasheet before initiating or completing a design.

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